

RoHS

COMPLIANT

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
30	0.004 at V _{GS} = 10 V	18	6.8 nC			
	0.005 at V _{GS} = 4.5 V	16	0.0110			

SO-8

Top View

8 D

D

6 D

5 D

S

S

S

G

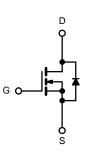
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FEATURES

- Halogen-free
- TrenchFET[®] Power MOSFET
- Optimized for High-Side Synchronous Rectifier Operation
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

Notebook CPU Core
 High-Side Switch



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A = 25 \text{ °C}$, unless otherwise noted						
Parameter		Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	30	V			
Gate-Source Voltage		V _{GS}			± 20	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C T _C = 70 °C	- I _D	18 16			
	T _A = 25 °C T _A = 70 °C		15 ^{b, c} 13 ^{b, c}	A		
Pulsed Drain Current		I _{DM}	50			
Continuous Source-Drain Diode Current	T _C = 25 °C T _A = 25 °C	I _S	3.8 2.1 ^{b, c}	-		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	22			
Avalanche Energy		E _{AS}	24	mJ		
Maximum Power Dissipation	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	P _D	4.5 2.8 2.5 ^{b, c} 1.6 ^{b, c}	W		
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ s}$	R _{thJA}	38	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	22	28	0/10	

Notes:

a. Base on T_C = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s. d. Maximum under Steady State conditions is 85 °C/W.



SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	1			1	1	1	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		28		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1.0		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V$, $V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	lace	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA	
Zero Gale voltage Drain Current	IDSS	V_{DS} = 30 V, V_{GS} = 0 V, T_{J} = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5$ V, V_{GS} = 10 V	20			А	
	D	V _{GS} = 10 V, I _D = 11 A		0.004			
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		0.005		Ω	
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 11 A		52		S	
Dynamic ^b					•		
Input Capacitance	C _{iss}			820		pF	
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		195			
Reverse Transfer Capacitance	C _{rss}			73			
T + 1 0 + 01	Qg	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 11 A		15 23	23	nC	
Total Gate Charge				6.8	10.2		
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 5 V, I_{D} = 11 A		2.5			
Gate-Drain Charge	Q _{gd}			2.3			
Gate Resistance	R _g	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			16	24	-	
Rise Time	tr	V_{DD} = 15 V, R_L = 1.4 Ω		12	18		
Turn-Off Delay Time	t _{d(off)}	${\sf I}_{\sf D}\cong$ 9 A, ${\sf V}_{\sf GEN}$ = 4.5 V, ${\sf R}_{\sf g}$ = 1 Ω		16	24		
Fall Time	t _f			10	20		
Turn-On Delay Time	t _{d(on)}			8	16	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		10	20	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	24		
Fall Time	t _f	-		8	15		
Drain-Source Body Diode Characterist					1	1	
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			25		
Pulse Diode Forward Current ^a	I _{SM}				50	A	
Body Diode Voltage	V _{SD}	I _S = 9 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			6	12	nC	
Reverse Recovery Fall Time	t _a	$I_F = 9 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$		8			
Reverse Recovery Rise Time		t _b		7		ns	

Notes:

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

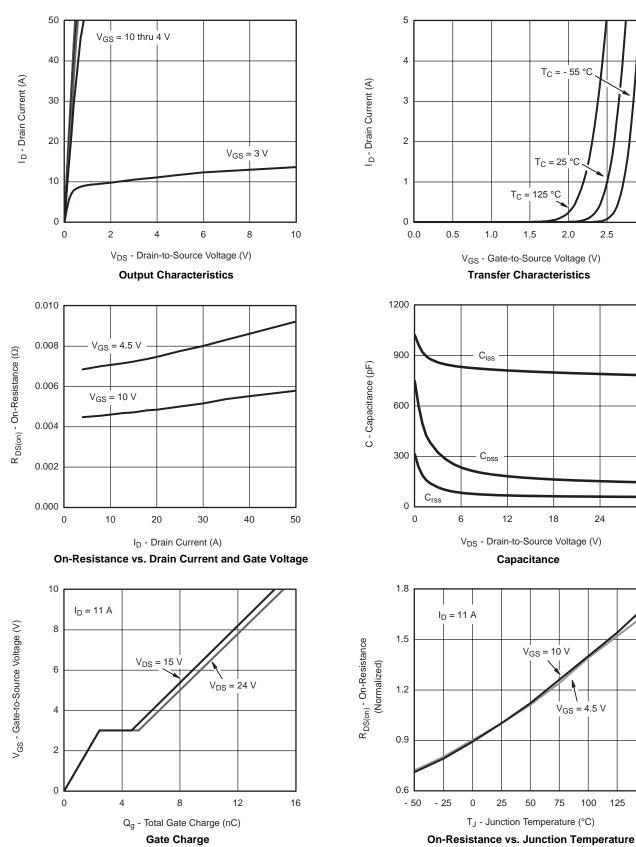


2.5

24

30

3.0

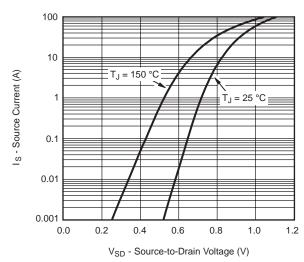


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

125

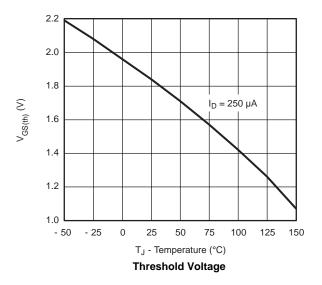
150

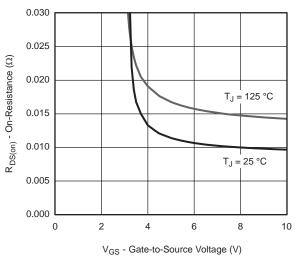




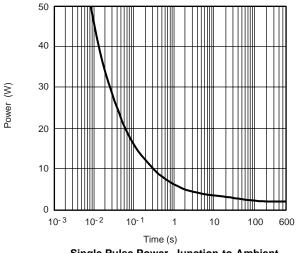
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



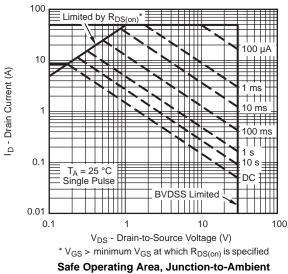




On-Resistance vs. Gate-to-Source Voltage

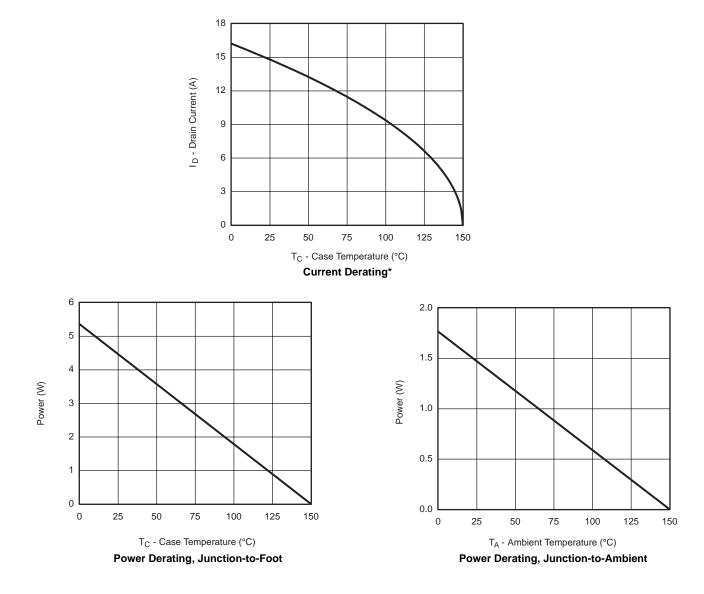








TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

Normalized Effective Transient Thermal Impedance

Normalized Effective Transient Thermal Impedance

0.02

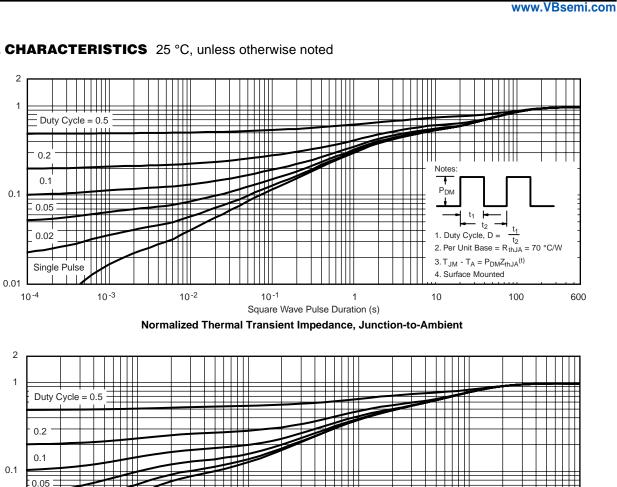
0.01

10-4

Single Pulse

1.1.1

10⁻³



10-1

Square Wave Pulse Duration (s) Normalized Thermal Transient Impedance, Junction-to-Foot

1

10-2

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



10

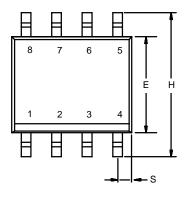
Bsemi

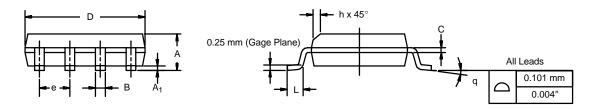




SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

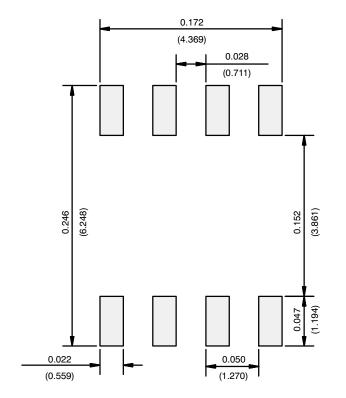




	MILLIM	IETERS	INCHES		
DIM	Min	Мах	Min	Max	
A	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498					



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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